



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. GILLP015X1	Application No.: 10/671,075
	Applicant: Johnston-Watt et al.	Group 2122 2192
	Filing Date September 25, 2003	

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
							Yes	No

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
ESK	1.	P.T. Wojciechowski; "The Nomadic PICT System. Release 1.0-alpha. Documentation and user's manual" 'Online!'; 19 Dec 2000 (2000-12-19), University of Cambridge; XP002282092; Retrieved from the Internet: URL:http://1srwww.epfl.ch/~pawel/npict-tutorial.ps.gz retrieved on 2004-05-24! page 30- page 31
ESK	2.	Kim Y G et al.: "Test cases generation from UML state diagrams"; IEE PROCEEDINGS: SOFTWARE, IEE, STEVENAGE, GB, vol. 146, no. 4, 24 Aug 1999 (1999-08-24), pages 187-192, XP006013720; ISSN: 1462-5970; page 189 – page 192.
ESK	3.	B.C. Pierce, D.N. Turner: "PICT: A Programming language Based on the Pi-Calculus"; 19 Dec 2000 (2000-12-19),; XP002282093; pages 1,2,21.
ESK	4.	Bemmerl T. et al.: "Programming Tools for Distributed Multiprocessor Computing Environments"; Future Generations Computer Systems; Elsevier Science Publishers, Amsterdam, NL; vol. 8, no. 1/3,; 1 July 1992 (1992-07-01), pages 221-234, XP000343134; ISSN: 0167-739X; page 229 – page 230.
ESK	5.	Furukawa, Z. et al.; American Federation of Information Processing Societies: "Agent: An Advanced Test-Case Generation System for Functional Testing;; Proceedings of the National Computer Conference; Las Vegas, June 16-19, 1986, AFIPS Conference Proceedings, Reston, AFIPS Press, US,; vol. Vol. 55, 1 June 1986 (1986-06-01),; page 527 – page 531.

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ESK	6. Rouger, A. et al.: "Test cases Generation From Formal Specifications"; Proceedings of the International Switching Symposium; Yokohama, Oct. 25 – 30, 1992, Tokyo, IEICE, JP; vol. vol. 2 SYMP. 14,; 25 Oct. 1992 (1992-10- 25), pages 439-443,; XP000337756; page 439 – page 442.
Examiner <i>C. D. Z.</i>	Date Considered <i>9/29/2005</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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EBK	1.	PCT/IPEA; PCT/GB 03/04205; Int'l Filing date 09/25/2003.
EBK	2.	PCT/ISA; PCT/GB 03/04205; Int'l Filing date 09/25/2003;.
EBK	3.	Written Opinion; PCT/GB 03/04205; Int'l Filing date 09/25/2003.
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